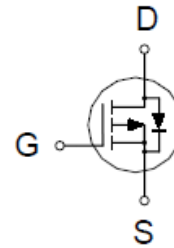
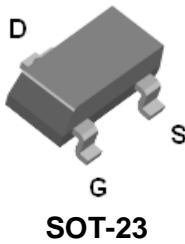


# P5102FM

## P-Channel Enhancement Mode MOSFET

### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-20V	45m $\Omega$ @ $V_{GS} = -4.5V$	-3.5A



### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25\text{ }^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	-20	V
Gate-Source Voltage		$V_{GS}$	$\pm 8$	
Continuous Drain Current	$T_A = 25\text{ }^\circ\text{C}$	$I_D$	-3.5	A
	$T_A = 70\text{ }^\circ\text{C}$		-2.8	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	-21	
Power Dissipation	$T_A = 25\text{ }^\circ\text{C}$	$P_D$	1.0	W
	$T_A = 70\text{ }^\circ\text{C}$		0.6	
Junction & Storage Temperature Range		$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$

### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		120	$^\circ\text{C} / \text{W}$

<sup>1</sup>Limited by maximum junction temperature.

# P5102FM

## P-Channel Enhancement Mode MOSFET

### ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)

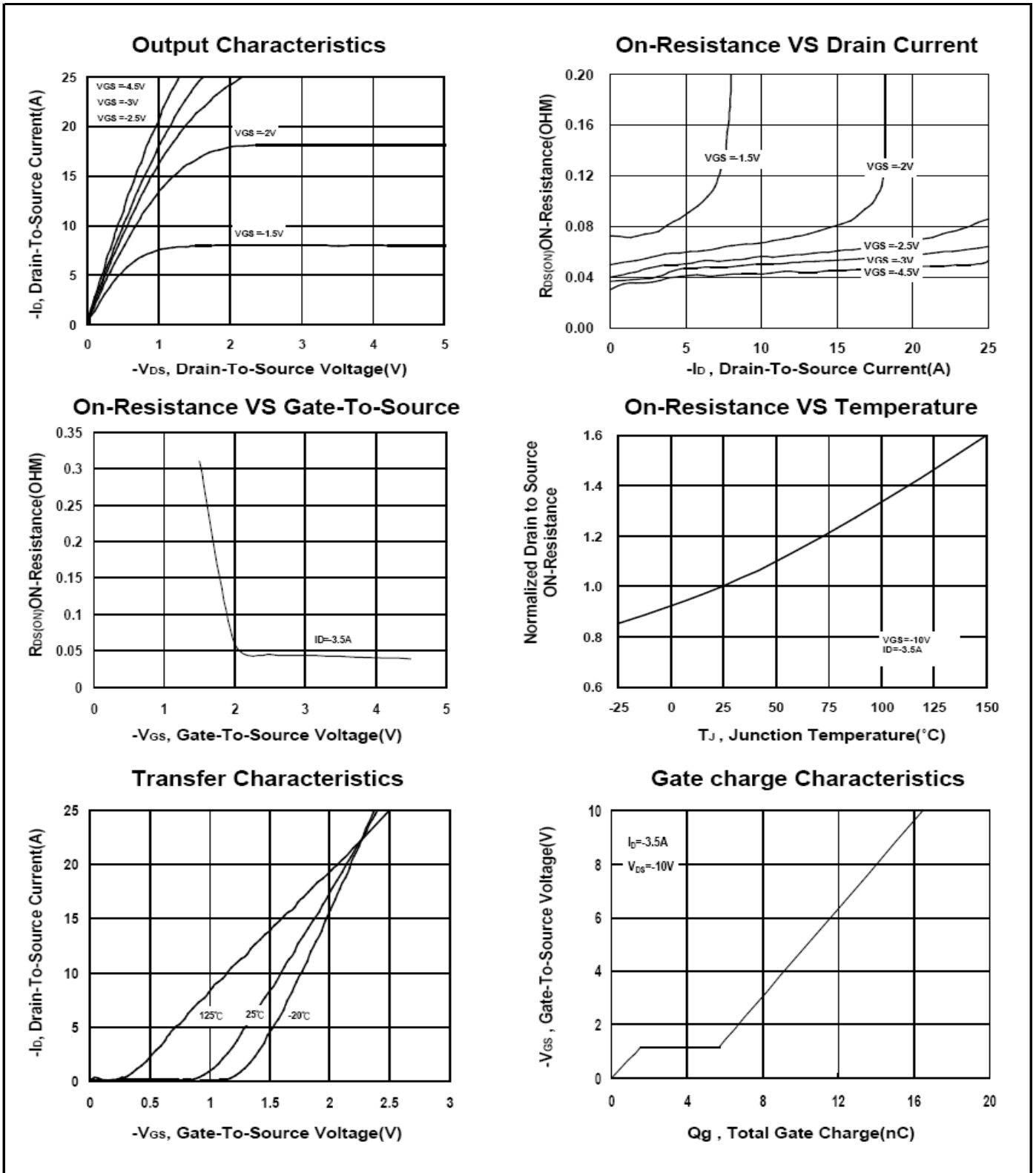
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-20			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-0.45	-0.6	-0.9	V
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±8V			±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V			-1	μA
		V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 70 °C			-10	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = -5V, V <sub>GS</sub> = -4.5V	-21			A
Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -2A		60	71	mΩ
		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -3.5A		48	55	
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3.5A		40	45	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = -5V, I <sub>D</sub> = -4A		17		S
<b>DYNAMIC</b>						
Input Capacitance	C <sub>iSS</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = -10V, f = 1MHz		1180		pF
Output Capacitance	C <sub>oss</sub>			185		
Reverse Transfer Capacitance	C <sub>rss</sub>			117		
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	V <sub>DS</sub> = 0.5V <sub>(BR)DSS</sub> , V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3.5A		16.7		nC
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>			1.8		
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>			4.6		
Turn-On Delay Time <sup>2</sup>	t <sub>d(on)</sub>	V <sub>DS</sub> = -10V I <sub>D</sub> ≅ -3.5A, V <sub>GS</sub> = -4.5V, R <sub>GEN</sub> = 3.3Ω		20		nS
Rise Time <sup>2</sup>	t <sub>r</sub>			36		
Turn-Off Delay Time <sup>2</sup>	t <sub>d(off)</sub>			45		
Fall Time <sup>2</sup>	t <sub>f</sub>			62		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTIC ( T<sub>J</sub> = 25 °C )</b>						
Continuous Current	I <sub>S</sub>				-3.5	A
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = -3.5A, V <sub>GS</sub> = 0V			-1.3	V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = -3.5A, dI <sub>F</sub> /dt = 100A / μS		30		nS
Reverse Recovery Charge	Q <sub>rr</sub>			14		nC

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

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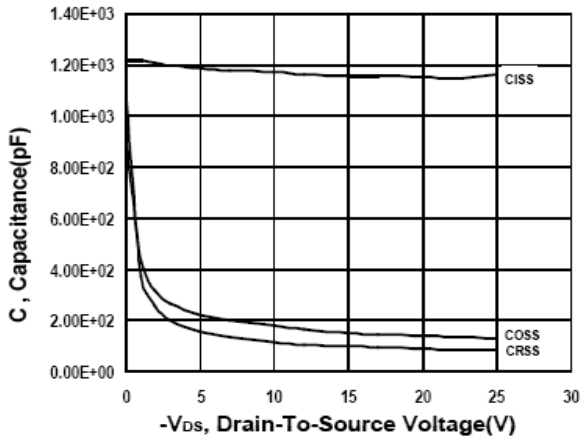
## P-Channel Enhancement Mode MOSFET



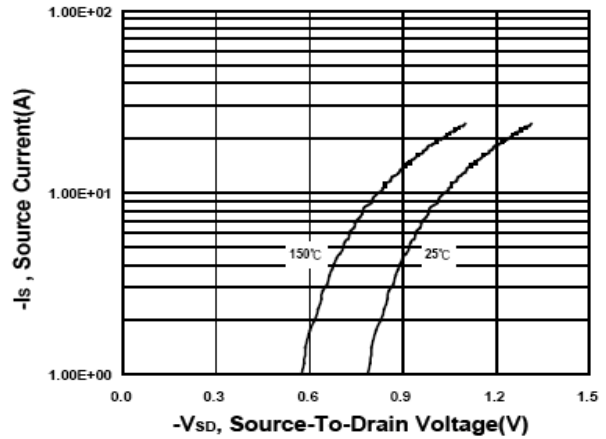
# P5102FM

## P-Channel Enhancement Mode MOSFET

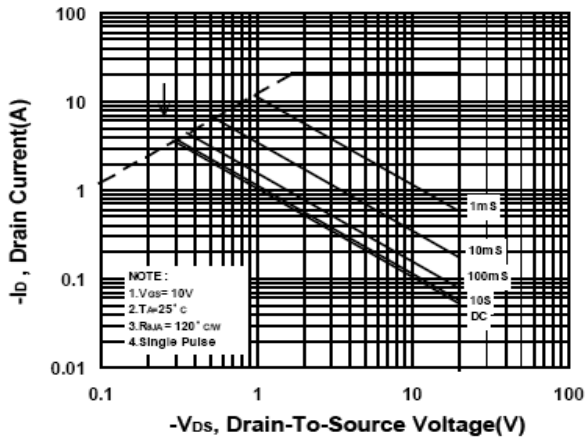
**Capacitance Characteristic**



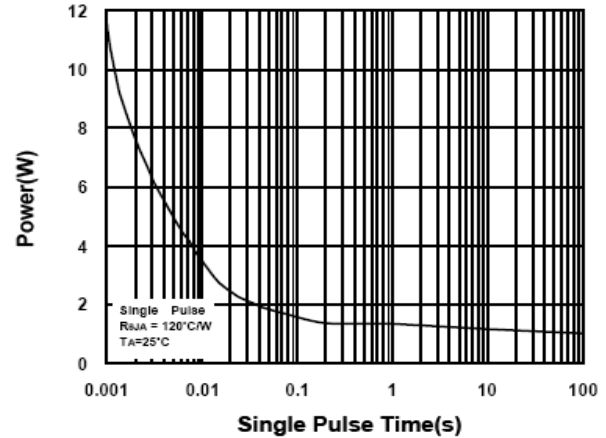
**Source-Drain Diode Forward Voltage**



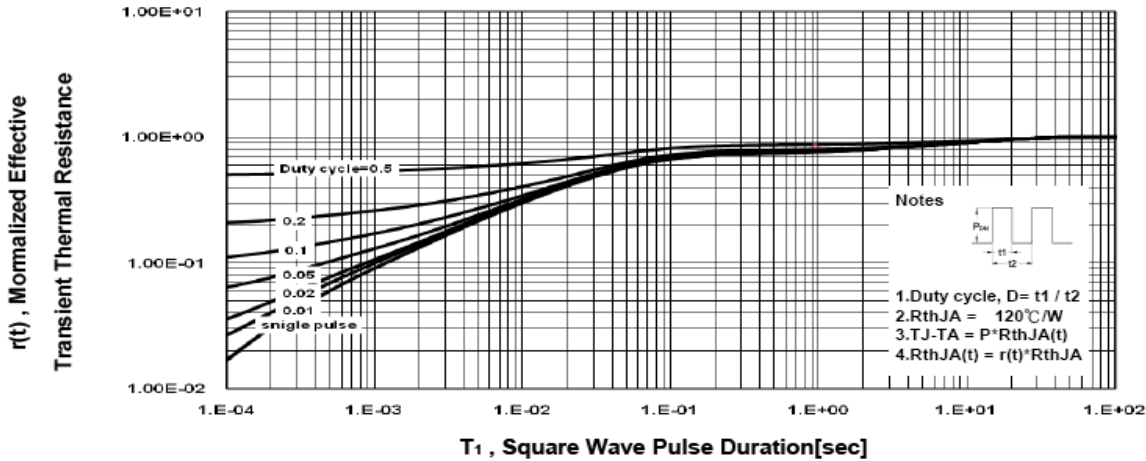
**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**



# P5102FM

## P-Channel Enhancement Mode MOSFET

### Package Dimension

### SOT-23-3 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A		1.05		H	0.1		0.2
B	2.4		3	I	0.3		0.6
C	1.4		1.73				
D	2.7		3.1				
E	1		1.31				
F	0		0.15				
G	0.3		0.5				

